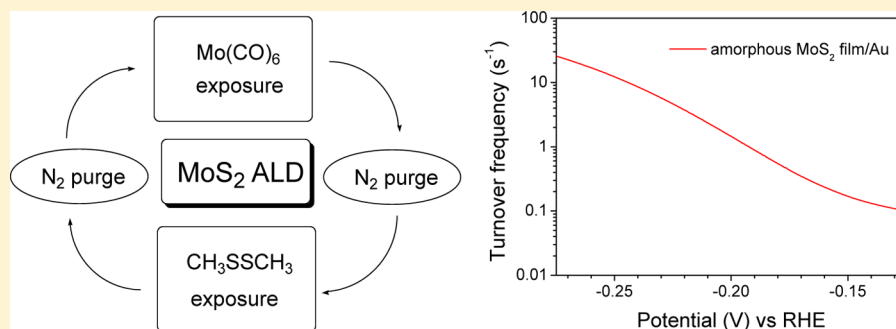


# High Turnover Frequency of Hydrogen Evolution Reaction on Amorphous MoS<sub>2</sub> Thin Film Directly Grown by Atomic Layer Deposition

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**S** Supporting Information



**ABSTRACT:** Recently amorphous MoS<sub>2</sub> thin film has attracted great attention as an emerging material for electrochemical hydrogen evolution reaction (HER) catalyst. Here we prepare the amorphous MoS<sub>2</sub> catalyst on Au by atomic layer deposition (ALD) using molybdenum hexacarbonyl (Mo(CO)<sub>6</sub>) and dimethyl disulfide (CH<sub>3</sub>SSCH<sub>3</sub>) as Mo and S precursors, respectively. Each active site of the amorphous MoS<sub>2</sub> film effectively catalyzes the HER with an excellent turnover frequency of 3 H<sub>2</sub>/s at 0.215 V versus the reversible hydrogen electrode (RHE). The Tafel slope (47 mV/dec) on the amorphous film suggests the Volmer–Heyrovsky mechanism as a major pathway for the HER in which a primary discharging step (Volmer reaction) for hydrogen adsorption is followed by the rate-determining electrochemical desorption of hydrogen gas (Heyrovsky reaction). In addition, the amorphous MoS<sub>2</sub> thin film is electrically evaluated to be rather conductive (0.22 Ω<sup>-1</sup> cm<sup>-1</sup> at room temperature) with a low activation energy of 0.027 eV. It is one of origins for the high catalytic activity of the amorphous MoS<sub>2</sub> catalyst.

## INTRODUCTION

MoS<sub>2</sub> is one of transition metal dichalcogenides (TMDs) which have layered two-dimensional structures. The TMD (MX<sub>2</sub>), where M is a transition metal of groups 4–10 and X is a chalcogen, is one of the potential materials for electronics, Li-ion batteries, and catalysis applications.<sup>1–3</sup> Among them, electrocatalyst for hydrogen evolution reaction (HER, 2H<sup>+</sup> + 2e<sup>-</sup> → H<sub>2</sub>) has been attracted for environmentally friendly hydrogen production from water splitting.<sup>4–8</sup> The HER, which constitutes half of the water-splitting reaction with oxygen evolution reaction, is most efficiently catalyzed on platinum by minimizing the overpotential ( $\eta$ ) required to drive the reduction of protons even at high reaction rates. However, Pt should be replaced with an inexpensive catalyst due to its high cost.

Widespread research has been focused on economic catalysts with high HER activity, which generally depends on Gibbs free energy of hydrogen adsorption ( $\Delta G_{H^*}$ ).<sup>9,10</sup> Recently, MoS<sub>2</sub> was identified as a biomimetic catalyst for the HER, owing to a small  $\Delta G_{H^*}$  on its edge sites (the hydrogen binding energy on MoS<sub>2</sub> is near to that on Pt).<sup>11</sup> It is well-known that only edge sites are active for the HER since the basal planes of MoS<sub>2</sub> are

catalytically inert.<sup>12–14</sup> Thus, MoS<sub>2</sub> with exposed edges can be a promising electrocatalyst for hydrogen evolution.

Ideal HER catalysts should have low Tafel slopes ( $b$ ) and high exchange current densities ( $J_0$ ) as shown in the Pt catalyst ( $b \sim 30$  mV/dec and  $J_0 \sim 10^{-3}$  A/cm<sup>2</sup>).<sup>15</sup> However, the bulk MoS<sub>2</sub> exhibits poor HER activity ( $b \sim 692$  mV/dec) due to the lack of the exposed edge sites and the large internal resistance in the bulk semiconductor.<sup>16</sup> There were several approaches to expose the active edges of MoS<sub>2</sub>: nanoparticles, mesoporous double-gyroid structure, vertically aligned films, and so on.<sup>17–20</sup> However, considering their sophisticated preparation processes, their catalytic performance is not satisfactory. Recently, Hu et al. reported that amorphous MoS<sub>2</sub> film prepared by a simple electrochemical method can achieve an excellent geometric current density of 15 mA/cm<sup>2</sup> at  $\eta = 200$  mV vs the reversible hydrogen electrode (RHE) with a Tafel slope of 40 mV/dec.<sup>21</sup> Since the amorphous MoS<sub>2</sub> films can be a facile approach to prepare highly active HER catalysts, here we propose a preparation method of the amorphous MoS<sub>2</sub> catalyst by atomic

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layer deposition (ALD) which is well-known as a film deposition method in semiconductor industry.

ALD is one of thin film growth methods in a vacuum, in which a thin film can be deposited by a self-limiting growth mechanism via chemisorption of precursor molecules.<sup>22</sup> Owing to the characteristic conformal growth behavior, ALD can be utilized to prepare catalysts on a highly porous substrate.<sup>23</sup>

Recently, MoS<sub>2</sub> HER catalyst was prepared by sulfurizing MoO<sub>3</sub> thin film at 600 °C which was grown on glassy carbon by ALD from Mo(CO)<sub>6</sub> and ozone.<sup>24</sup> They obtained vertically aligned and crystallized MoS<sub>2</sub> which exhibited a geometric current density of 0.15 mA/cm<sup>2</sup> at  $\eta$  = 200 mV. Loh et al. reported direct ALD of MoS<sub>2</sub> using MoCl<sub>5</sub> and H<sub>2</sub>S as Mo and S precursors, respectively.<sup>25</sup> However, the as-grown film was also polycrystalline due to the high growth temperature of 300 °C. Very recently, we have demonstrated a novel chemical route for ALD of MoS<sub>2</sub> using Mo(CO)<sub>6</sub> and dimethyl disulfide (CH<sub>3</sub>S<sub>2</sub>CH<sub>3</sub>, DMDS) through which the amorphous MoS<sub>2</sub> film could be grown at 100 °C.<sup>26</sup> In this work, the HER performances of the amorphous MoS<sub>2</sub> directly grown on Au by ALD are investigated to unravel its intrinsic catalytic activity.

## EXPERIMENTAL SECTION

**Preparation and Characterization of MoS<sub>2</sub> Catalyst.** For the catalyst preparation, Ti (10 nm) and Au (100 nm) thin films were subsequently deposited on a Si wafer by sputtering, and then the wafer was cleaved to several pieces of 1 × 2 cm<sup>2</sup>. The amorphous MoS<sub>2</sub> was grown at 100 °C on the Au substrate by repeating the ALD sequence: Mo(CO)<sub>6</sub> exposure (4 s)—purging (30 s)—DMDS exposure (1.5 s)—purging (10 s).<sup>26</sup> The geometric area (1 cm<sup>2</sup>) of the MoS<sub>2</sub> catalyst was defined with a Kapton tape (see Figure S1), and then the specimen was connected to a metal wire using silver paste for the electrochemical evaluation of the HER performance.

X-ray photoelectron spectroscopic (XPS) spectra were obtained on a PHI 5000 Versaprobe (ULVAC PHI) using monochromatic Al K $\alpha$  emission. Binding energies were calibrated by using the Au 4f<sub>7/2</sub> peak (84.0 eV). The thickness of the grown film was measured by spectroscopic ellipsometry (SE, MG-1000, NanoView). The incident angle of the polarized light in the SE was fixed at around 70°, and the incident light has a spectral range of 1.5–5.0 eV. The measured data by SE were fitted with a Tauc–Lorentz dispersion function in order to determine the thickness.<sup>27</sup> Scanning electron microscopic (SEM) images were taken with ultrahigh-resolution field emission SEM (Hitachi, S-5500) without any coating of metal. Grazing incidence X-ray reflectivity (XRR) data were collected in 0.01° increments and 4 s count times on a high-resolution X-ray diffractometer (Empyrean, PANalytical). XRR data were analyzed with X'pert reflectivity ver. 1.0.

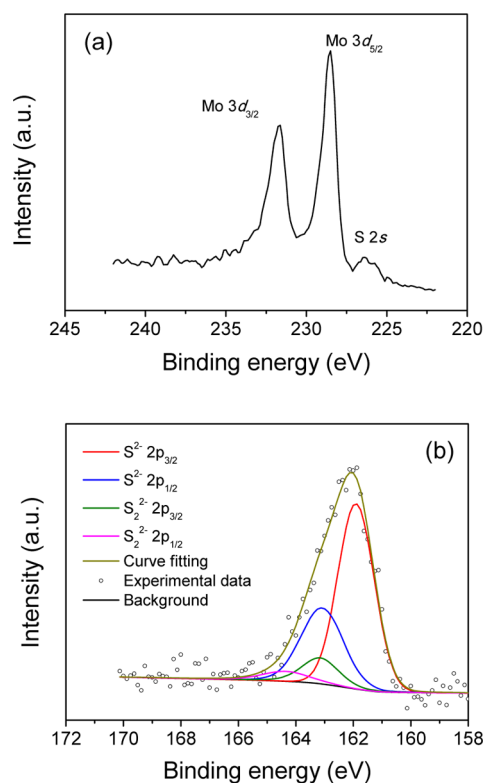
**Electrochemical Characterization of MoS<sub>2</sub>.** The electrochemical measurements were performed in a three-electrode electrochemical cell using a Bio-Logic potentiostat (SP-150). All measurements were performed in 100 mL of 0.5 M sulfuric acid (H<sub>2</sub>SO<sub>4</sub>) electrolyte prepared in Millipore water (18 M $\Omega$  cm) purged with H<sub>2</sub> gas (99.999%). A Hg/Hg<sub>2</sub>SO<sub>4</sub> (K<sub>2</sub>SO<sub>4</sub> saturated) electrode and a graphite rod were used as a reference electrode and a counter electrode, respectively. The MoS<sub>2</sub> film prepared on Au was used as a working electrode. The reference electrode was calibrated to the reversible hydrogen potential using Pt wires for both working and counter electrodes in the same 0.5 M H<sub>2</sub>SO<sub>4</sub> electrolyte under the H<sub>2</sub> gas purge. This calibration gives a shift of  $-0.700 \pm 0.005$  V versus the RHE. The polarization curves for the HER were measured using linear sweep voltammetry (LSV) beginning at 0.1 V and ending at  $-0.3$  V vs RHE with a scan rate of 5 mV/s. Before each LSV, the series resistance of the electrochemical cell was determined by electrochemical impedance measurement performed at open circuit potential from 200 kHz to 50 mHz, using an ac amplitude of 25 mV. The series resistance was measured to be  $\sim 2.5$   $\Omega$ , and the polarization curves were corrected for the ohmic potential drop ( $iR$ ) losses (see Figure

S2). In order to estimate the effective surface area of the catalyst film, the double-layer capacitance ( $C_{dl}$ ) of the catalyst were determined by cyclic voltammetry in a potential range of 0.1–0.2 V with various scan rates (20, 40, 60, 80, and 100 mV/s; see Figure S3).

**Electrical Characterization of MoS<sub>2</sub>.** In order to evaluate electrical conductivity, ALD MoS<sub>2</sub> thin film (12.7 nm) was grown on SiO<sub>2</sub> (300 nm)/Si substrate at 100 °C. Coplanar Au electrodes were formed on the surface of the film by thermal evaporation through a shadow mask. The distance between the neighboring electrodes was 400  $\mu$ m, and the width of each electrode was 400  $\mu$ m. Current–voltage characteristic measurements were performed at a temperature range of 110–300 K between the neighboring two electrodes in a vacuum probe station (MS-Tech MSVC) using a semiconductor parameter analyzer (Keithley 4200 SCE).

## RESULTS AND DISCUSSION

**Characterization of Amorphous MoS<sub>2</sub> Catalyst.** In Figure 1, the ALD MoS<sub>2</sub> film on Au is characterized by XPS.



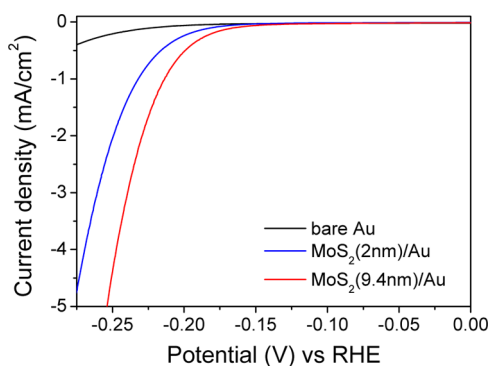
**Figure 1.** XPS spectra of MoS<sub>2</sub> film on Au: Mo 3d (a) and S 2p (b) peaks. The binding energies were calibrated by using the Au 4f<sub>7/2</sub> peak (84.0 eV). The curve fitting was performed with two constraints: the intensity ratio (1:2) and the binding energy difference (1.18 eV) of S 2p<sub>1/2</sub> and 2p<sub>3/2</sub> for both S<sup>2-</sup> and S<sub>2</sub><sup>2-</sup> ions.

The characteristic binding energies of Mo 3d<sub>3/2</sub> and 3d<sub>5/2</sub>, which are attributed to Mo<sup>4+</sup>, were observed at 231.6 and 228.5 eV, respectively.<sup>21,28–30</sup> For the binding energies of S 2p<sub>1/2</sub> and 2p<sub>3/2</sub> for divalent sulfide ion (S<sup>2-</sup>), the 2p<sub>3/2</sub> peak was observed at 162.0 eV. However, the 2p<sub>1/2</sub> peak is not clearly resolved but may be hidden as a shoulder of the 2p<sub>3/2</sub> peak. The stoichiometric ratio (S/Mo), estimated from peak intensities on the surface, is around 2.19, suggesting that the film is close to MoS<sub>2</sub>. The slightly higher stoichiometric ratio can be explained by the presence of MoS<sub>3</sub> in the film. Several groups reported the amorphous MoS<sub>3</sub> thin film which corresponds to a formal charge state of Mo<sup>4+</sup>(S<sup>2-</sup>)(S<sub>2</sub><sup>2-</sup>).<sup>21,28,29,31</sup>

It is well-known that the peaks of S  $2p_{1/2}$  and  $2p_{3/2}$  for  $S_2^{2-}$  appear at higher binding energies than those of  $S^{2-}$ . In order to confirm the presence of the  $S_2^{2-}$  ion, the S 2p spectrum in Figure 1 was deconvoluted and fitted with two doublets, i.e.,  $2p_{3/2}$  (161.9 eV) and  $2p_{1/2}$  (163.1 eV) for the  $S^{2-}$  and  $2p_{3/2}$  (163.2 eV) and  $2p_{1/2}$  (164.4 eV) for the  $S_2^{2-}$  ion.<sup>21,29</sup> The ratio of  $S^{2-}$  to  $S_2^{2-}$  was evaluated to be  $\sim 6.4$  using the intensities of the doublets. By using the ratio of S ions, the stoichiometric ratio (S/Mo) can be calculated to be  $\sim 2.27$ , which agrees well with the measured value ( $\sim 2.19$ ).

When our ALD process was performed on  $SiO_2/Si$  substrate in the previous report,<sup>26</sup> although the as-grown film was amorphous in X-ray diffraction, the film clearly showed two characteristic Raman modes of  $E_{2g}^1$  and  $A_{1g}$  associated with in-plane and out-of-plane vibrational modes of S–Mo–S, respectively.<sup>32,33</sup> Unlike the amorphous films grown on  $SiO_2/Si$  substrates, no significant peaks of the  $E_{2g}^1$  and  $A_{1g}$  modes were observed from the amorphous  $MoS_2/Au$  specimen (data not shown). This indicates that the grown film is even more disordered on Au than on  $SiO_2/Si$  substrate.

**Hydrogen Evolution Catalysis on Amorphous  $MoS_2$  Thin Film.** The amorphous films on Au were used as a working electrode for hydrogen evolution in 0.5 M  $H_2SO_4$  solution using a typical three-electrode setup. Figure 2 shows polar-



**Figure 2.** Polarization curves ( $iR$ -corrected) of  $MoS_2$  films measured in an aqueous solution of  $H_2SO_4$  (0.5 M) with a scan rate of 5 mV/s.

ization curves of two  $MoS_2$  films with different thicknesses (2.0 and 9.4 nm, measured by SE) and a bare Au specimen as a control sample. Each curve was corrected for ohmic potential drop ( $iR$ ) losses (see Figure S2). Comparing to the cathodic current density ( $j$ ) of Au specimen ( $j = 62 \mu A/cm^2$  at  $\eta = 200$  mV), the amorphous  $MoS_2$  films show much higher current densities at lower overpotential. In addition, the thicker film ( $j = 532 \mu A/cm^2$  at  $\eta = 200$  mV) shows better activity than the thinner ( $j = 241 \mu A/cm^2$  at  $\eta = 200$  mV). The high catalytic activity of the ALD- $MoS_2$  is more obvious when compared with the onset potential at which the hydrogen evolution starts. Because it is difficult to visually recognize the initiation of the hydrogen evolution, the onset potential is defined as the overpotential required for a designated current density of  $100 \mu A/cm^2$ . Comparing to the onset potential (222 mV) of the bare Au in Figure 2, the thick and thin  $MoS_2$  films show much smaller onset potentials of 165 and 181 mV, respectively, which are well agreed with the previous reports.<sup>8</sup>

The electrode kinetics in electrochemical reactions can be explained by the Butler–Volmer equation.<sup>34</sup> Under the assumption of no mass-transfer effect, the equation can be simplified to

$$j = j_0 [e^{(1-\beta)\eta F/RT} - e^{-\beta\eta F/RT}] \quad (1)$$

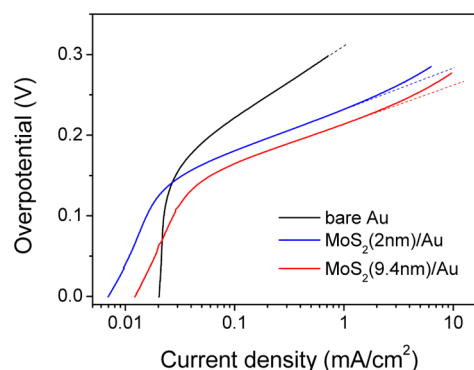
where  $F$  and  $R$  are the Faraday constant and gas constant, respectively, and  $\beta$  is the symmetry factor ( $\beta \sim 0.5$ ) which is an indicator of the symmetry of the energy barrier for the reaction. The exchange current density ( $j_0$ ) is a quantitative measure of the rate of reaction at equilibrium (i.e.,  $\eta = 0$ ). When the overpotential is largely negative as the linear portion of the polarization curve in Figure 2, the current density can be approximated only with the second term (cathodic current density), which is called the Tafel equation:

$$j = -j_0 e^{-\beta\eta F/RT} \quad (2)$$

The figures of merit for electrocatalytic activity can be obtained from the slope and the intercept in the  $\log j$  axis by fitting the linear portion of the polarization curve to the semilogarithmic equation of  $\eta = a + b \log j$ . Table 1 summarizes the Tafel slopes ( $b$ ) and  $j_0$  values obtained from the Tafel plots in Figure 3.

**Table 1. Figures of Merit for Electrocatalytic Activity of  $MoS_2$  Films**

samples	Tafel slope (mV/dec)	$J_0$ ( $\mu A/cm^2$ )	onset potential (V)	TOF at 0.2 V vs RHE ( $H_2/s$ )
bare Au	88	0.293	−0.222	
$MoS_2$ (2.0 nm)	50	0.024	−0.181	
$MoS_2$ (9.4 nm)	47	0.027	−0.165	1.45



**Figure 3.** Tafel plots of  $MoS_2$  films measured in an aqueous solution of  $H_2SO_4$  (0.5 M) with a scan rate of 5 mV/s. The dotted lines are drawn for an eye guide of the Tafel slopes.

For the bare Au specimen, the exchange current density is  $0.293 \mu A/cm^2$ , which agrees well with the values ranged in the  $10^{-8}$ – $10^{-7}$  A/cm<sup>2</sup> in the previous reports.<sup>4,12,35,36</sup> The  $J_0$  values of  $MoS_2$  films are about 1 order of magnitude lower than that of the bare Au. However, since the  $MoS_2$  films have much smaller Tafel slopes (47–50 mV/dec) than that (88 mV/dec) of Au, they show more excellent HER activity in Figure 2.

According to the classical theory on the HER kinetics, the Tafel slope is determined by the transfer coefficient ( $\alpha$ ) which has a particular value depending on the mechanism.<sup>37</sup>

$$b = \frac{\partial \eta}{\partial \log j} = -\frac{RT}{\alpha F} \ln e \quad (3)$$

Three possible reaction steps are known for the HER in acidic media:



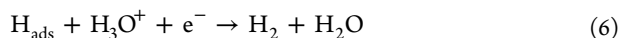
discharge step (Volmer reaction):



catalytic recombination step (Tafel reaction):



electrochemical desorption step (Heyrovsky reaction):



For hydrogen evolution, there are two possible pathways: Volmer–Tafel (VT) and Volmer–Heyrovsky (VH) mechanisms. Furthermore, the transfer coefficient is different depending on which step is the rate-determining step (rds). For the Volmer (rds)–Tafel mechanism ( $\bar{\text{V}}\text{T}$ , the bar denotes the rds), in which the rate-determining Volmer step is followed by the Tafel step,  $\alpha = \beta = 0.5$ , and this mechanism has a Tafel slope of 120 mV/dec by eq 3. However, when the Tafel step is the rds, the  $\bar{\text{V}}\text{T}$  mechanism has a Tafel slope of 30 mV/dec ( $\alpha = 2$  and  $\beta = 0.5$ ). For the VH mechanism, the Tafel slopes are 120 mV/dec for the  $\bar{\text{V}}\text{H}$  mechanism ( $\alpha = \beta = 0.5$ ) and 40 mV/dec for the  $\text{V}\bar{\text{H}}$  mechanism ( $\alpha = 1.5$  and  $\beta = 0.5$ ).

Considering the Tafel slopes ( $b = 47$  mV/dec) from the amorphous  $\text{MoS}_2$  films, the  $\text{V}\bar{\text{H}}$  mechanism might be the main pathway for the HER on our catalyst. Several groups also reported similar Tafel slopes from various forms of  $\text{MoS}_2$ : nanoparticles on reduced graphene (40 mV/dec),<sup>17</sup> electrochemically grown film on glassy carbon (41 mV/dec),<sup>21</sup> amorphous film on nanoporous gold (41 mV/dec),<sup>36</sup> vertically aligned film (44 mV/dec),<sup>24</sup> double-gyroid network (50 mV/dec),<sup>18</sup> and nanocrystals on gold (55–60 mV/dec).<sup>12</sup> However, the deviation of the Tafel slope from the theoretical value (40 mV/dec) of the  $\text{V}\bar{\text{H}}$  mechanism reveals that other reaction pathway partially contributes to the reaction. Previously, it is reported that a Tafel slope of 60 mV/dec can be obtained when a chemical rearrangement step is inserted as a rds between the Volmer and Heyrovsky steps.<sup>14,38</sup> If proton adsorption is much stronger on a certain type of active sites than on others, the strongly adsorbed  $\text{H}_{\text{ads}}$  will not be able to easily reach a necessary condition for the Heyrovsky step. Therefore, the surface rearrangement of  $\text{H}_{\text{ads}}$  would be rate-determining. Because of significant heterogeneity of the surface sites or the presence of both  $\text{S}^{2-}$  and  $\text{S}_2^{2-}$  in the amorphous  $\text{MoS}_2$  catalyst, it would be possible that some active sites might bind the surface hydrogen more strongly than the other.

Even though the  $j_0$  is an inherent measure of activity for the HER, it is sometimes unfair to compare the activities of catalysts with the  $j_0$  values since the geometric area of catalyst can be largely different from a catalytically effective surface area due to their surface roughness or porosity. In this point of view, turnover frequency (TOF) per active site, which is defined as the number of hydrogen molecules evolved on an active site in a time period (e.g., in 1 s), is the best figure of merit to compare the catalytic activity.<sup>14,39</sup> Assuming the cathodic current is entirely attributed to the HER, the TOF can be calculated from the  $j$  (e.g., in  $\text{A}/\text{cm}^2$ ) by using an equation of  $\text{TOF} = j/nFN$  with a known value of number of active sites ( $N$ ) in an unit area (e.g., in  $\text{cm}^2$ ) where  $n$  is the stoichiometric number of electrons consumed in the electrode reaction (i.e.,  $n = 2$  for the HER). Because of the different nature of various  $\text{MoS}_2$  catalysts and their preparation methods, several approaches have been used to determine the  $N$  values (see the Supporting Information of ref 14). Because our ALD-grown

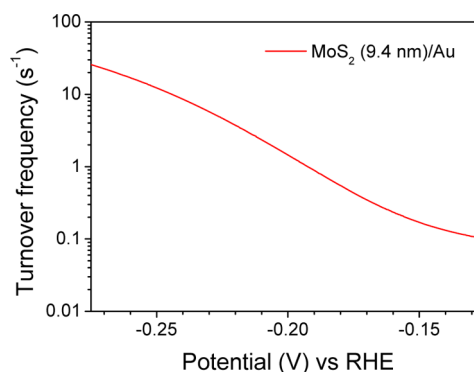
film is amorphous, the structure and properties of  $\text{MoS}_2$  can be assumed to be isotropic. Therefore, the  $N$  value may be estimated from the amorphous film density ( $d$ ) by

$$N = R_f(N_A d/M_f)^{2/3} \quad (7)$$

where  $N_A$  and  $M_f$  are Avogadro's number and formula weight of  $\text{MoS}_2$ , respectively, and  $R_f$  is a surface roughness factor defined as a ratio of the real surface area to the geometric area.

In this work, the film density ( $d$ ) of the amorphous  $\text{MoS}_2$  was determined by grazing incidence X-ray reflectivity (XRR, Figure S4). The measured density ( $\sim 2.9 \text{ g}/\text{cm}^3$ ) of the amorphous film, grown at  $100^\circ\text{C}$ , is much lower than that ( $5.06 \text{ g}/\text{cm}^3$ ) of crystalline  $\text{MoS}_2$ .<sup>40</sup> In general, as amorphous films are grown at lower temperatures by ALD, they have lower density.<sup>41</sup> Assuming a flat  $\text{MoS}_2$  ( $R_f \sim 1$ ), the number of active sites on the flat surface of the amorphous  $\text{MoS}_2$  is approximately calculated to be  $\sim 4.9 \times 10^{14}/\text{cm}^2$  by eq 7. Because of the low density of the amorphous film, this value is roughly a factor of 2 lower than the number of active sites ( $1.164 \times 10^{15}/\text{cm}^2$ ) on a flat surface of crystalline  $\text{MoS}_2$ .<sup>42</sup> However, as shown in SEM images in Figure S5, the surface of the amorphous films is not flat because the film was grown on Au with crystalline grains. Thus,  $R_f \neq 1$  and the roughness factor should be considered when calculating the  $N$  value. The  $R_f$  of the amorphous film was determined by the ratio of double layer capacitance ( $C_{\text{dl}}$ ) of the amorphous  $\text{MoS}_2$  to that ( $66.7 \mu\text{F}/\text{cm}^2$ ) of flat crystalline  $\text{MoS}_2$ ,<sup>43</sup> since the  $C_{\text{dl}}$  is linearly proportional to catalytically active surface area.<sup>44</sup> It is assumed that the  $C_{\text{dl}}$  values of amorphous film and the crystalline  $\text{MoS}_2$  are the same in the case of flat surfaces. The  $C_{\text{dl}}$  value of the amorphous film (9.4 nm) was estimated to be  $\sim 152 \mu\text{F}/\text{cm}^2$  by cyclic voltammetry (see Figure S3). Therefore, the roughness factor of the film is  $\sim 2.28$ , and the  $N$  value is around  $1.12 \times 10^{15}/\text{cm}^2$  by eq 7.

The TOF (per active site) can be calculated by using the equation of  $\text{TOF} = j/nFN$ , where  $N = 1.12 \times 10^{15}/\text{cm}^2$ . The TOF of the amorphous  $\text{MoS}_2$  (9.4 nm)/Au catalyst is shown in Figure 4 within the Tafel region in order to guarantee that the



**Figure 4.** Turnover frequency (TOF) of amorphous  $\text{MoS}_2$  film (9.4 nm)/Au.

HER is controlled by electrode kinetics without any other effect (e.g., mass transfer). In terms of the TOF per active site, the most active catalyst of  $\text{MoS}_2$  is vacuum-deposited nanocrystals on Au, of which TOFs are 1 and  $10 \text{ H}_2/\text{s}$  at overpotentials of  $\sim 0.1$  and  $\sim 0.16 \text{ V}$ , respectively.<sup>12</sup> The same TOFs can be achieved on our amorphous film at overpotentials of 0.193 and 0.244 V, respectively. Even though the amorphous  $\text{MoS}_2$  shows lower TOFs than the nanocrystals, the intrinsic activity (e.g.,

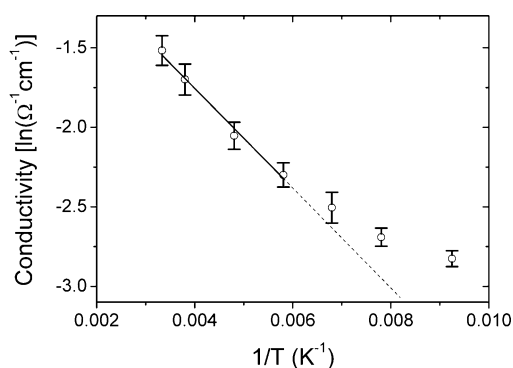
TOF = 3 H<sub>2</sub>/s at 0.215 V and 1.45 H<sub>2</sub>/s at 0.2 V) of the ALD-MoS<sub>2</sub> is comparable to that of crystalline thiomolybdate cluster catalyst which has the second highest TOF (3 H<sub>2</sub>/s at an overpotential of 0.20 V) among all molybdenum sulfide catalysts ever reported.<sup>14</sup> Furthermore, our ALD-MoS<sub>2</sub> has the highest TOF among those of the amorphous MoS<sub>x</sub> ever reported. For example, comparing to the TOF (e.g., TOF = 0.8 H<sub>2</sub>/s at 0.22 V and 2 H<sub>2</sub>/s at 0.24 V) of the amorphous MoS<sub>x</sub> film grown by cyclic voltammetric method,<sup>21</sup> our catalyst shows 4 times higher TOF (per active site) at the same overpotential (i.e., TOF = 3.7 H<sub>2</sub>/s at 0.22 V and 8.5 H<sub>2</sub>/s at 0.24 V). This high TOF is the biggest advantage of the ALD-MoS<sub>2</sub> catalyst for the HER. Although the exchange current density of the ALD-MoS<sub>2</sub> is not high due to the lower roughness factor in comparison to the other forms of MoS<sub>2</sub>, it may be overcome by using porous substrates with large surface area. Furthermore, the ALD is one of the best methods when forming a conformal film on a porous substrate.<sup>23</sup>

The stability of a HER catalyst is another practical parameter to consider when designing long-term operations. A cyclic voltammetry test for 1000 cycles was performed to assess the electrochemical stability of the ALD-MoS<sub>2</sub> in an acidic environment (0.5 M H<sub>2</sub>SO<sub>4</sub>). Unfortunately, the amorphous ALD-MoS<sub>2</sub> on Au shows poor stability (Figure S6). There are many reports for the excellent stability of the *crystalline* MoS<sub>2</sub> on various substrates such as Au, graphene, and glassy carbon.<sup>17,19,24</sup> However, the good stability of the *amorphous* MoS<sub>2</sub> is very rarely reported. It is recently studied that the factors contributing to the activity loss of the amorphous MoS<sub>2</sub> may be due to the surface adsorbates, which can poison the active sites, or delamination of MoS<sub>2</sub> from the substrate.<sup>42</sup> Sun et al. also demonstrated that the catalytic stability could be excellent when the amorphous MoS<sub>2</sub> was prepared on Mo foil by an in-situ fabrication approach to avoid the delamination.<sup>45</sup> However, to the extent of our knowledge, no reports were made on excellent stability of the amorphous MoS<sub>2</sub>/Au catalyst, which could possibly be due to the poor adhesion of the MoS<sub>2</sub> on Au. Therefore, it is necessary to replace Au with cheap and porous substrates (e.g., carbon fiber paper) which can provide a surface for strong adhesion of amorphous MoS<sub>2</sub>. Substrate-related issues are beyond the scope of this work, and further study will be presented elsewhere.

#### Electrical Conductivity of Amorphous MoS<sub>2</sub> Thin Film.

One more concern for the amorphous MoS<sub>2</sub> is the electrical conductivity ( $\sigma$ ) of the film. The crystalline bulk MoS<sub>2</sub> has a poor catalytic activity due to the large internal resistance, especially in the direction perpendicular to the MoS<sub>2</sub> layers. The electrical conductivity of crystalline MoS<sub>2</sub> is extremely anisotropic so that the conductivity ( $10^{-5}$ – $10^{-4}$   $\Omega^{-1}$  cm<sup>-1</sup>) perpendicular to the layers is approximately 3 orders of magnitude smaller than that ( $10^{-2}$ – $10^{-1}$   $\Omega^{-1}$  cm<sup>-1</sup>) parallel to the layer.<sup>16,46,47</sup> In Figure 5, the conductivity of the amorphous film was evaluated at a temperature range of 110–300 K by using a simple two-probe measurement setup between two coplanar Au electrodes on the film surface. The conductivity of the film is around  $0.22 \pm 0.02$   $\Omega^{-1}$  cm<sup>-1</sup> at room temperature. This value is similar to or slightly higher than the conductivity parallel to the layer of the bulk.<sup>46</sup>

In addition, the conductivity of the amorphous film logarithmically increases with temperature due to the semi-conducting nature. Such a thermally activated conductivity can be represented by the Boltzmann law:



**Figure 5.** Arrhenius plot of conductivity of amorphous MoS<sub>2</sub> thin film. It was measured between two coplanar surface electrodes (Au) on MoS<sub>2</sub> (10 nm)/SiO<sub>2</sub> (300 nm)/Si substrate.

$$\sigma = \sigma_0 e^{-E_a/kT} \quad (8)$$

where  $E_a$  and  $k$  are the activation energy and the Boltzmann constant, respectively. Using the slope of the Arrhenius plot in a range of 170–300 K in Figure 5, we determined the activation energy to be  $\sim 0.027 \pm 0.004$  eV, which is similar to or lower than the activation energy (0.03–0.08 eV) for the conduction parallel to the layer in the bulk.<sup>48,49</sup> The deviation from the linearity at lower temperatures than 150 K can be explained with hopping of electrons through localized states which becomes dominant at lower temperatures.<sup>48</sup> Consequently, another reason for the high catalytic activity of the amorphous film would be its isotropic high conductivity with a low activation energy.

## CONCLUSIONS

For facile preparation of amorphous MoS<sub>2</sub> catalyst, we utilize direct growth of amorphous MoS<sub>2</sub> by ALD using Mo(CO)<sub>6</sub> and DMDS. The amorphous MoS<sub>2</sub> thin film exhibits excellent HER activity with a high TOF (3 H<sub>2</sub>/s at an overpotential of 0.215 V) per active site. This is the highest TOF reported to date for amorphous MoS<sub>2</sub> catalyst. The Tafel slope of 47 mV/dec reveals that the HER on the amorphous film is catalyzed via the Volmer–Heyrovsky mechanism of which the rate-determining step is the electrochemical desorption of hydrogen. In addition, the amorphous MoS<sub>2</sub> has an electrical conductivity of  $0.22 \pm 0.02$   $\Omega^{-1}$  cm<sup>-1</sup> at room temperature with an activation energy of  $0.027 \pm 0.004$  eV.

## ASSOCIATED CONTENT

### Supporting Information

Digital image of MoS<sub>2</sub> catalyst specimen, correction of ohmic potential drop, SEM images, XRR data, double-layer capacitance, electrochemical impedance measurements, and stability test. This material is available free of charge via the Internet at <http://pubs.acs.org>.

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S.S. and Z.J. equally contributed to this work.

### Notes

The authors declare no competing financial interest.

## ■ ACKNOWLEDGMENTS

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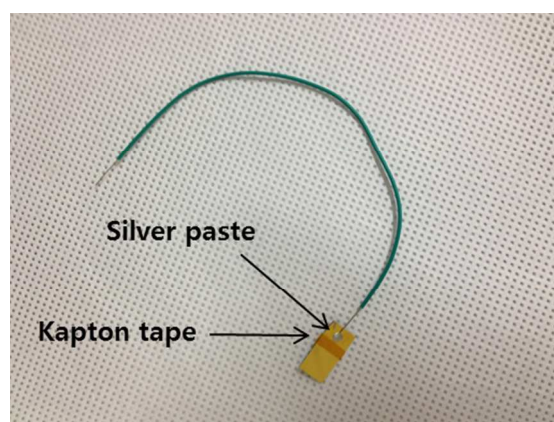
## SUPPORTING INFORMATION

### High turnover frequency of hydrogen evolution reaction on amorphous MoS<sub>2</sub> thin film directly grown by atomic layer deposition

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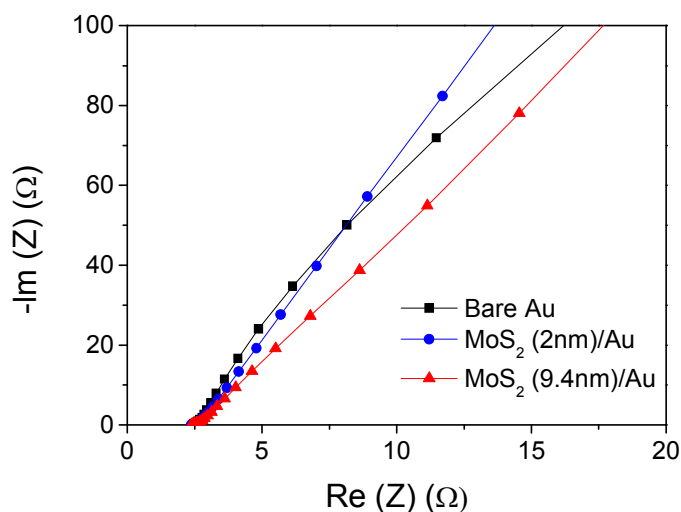
**Preparation of working electrode with catalyst:** After the ALD of MoS<sub>2</sub> on Au/Ti/Si substrate, the geometrical area of the catalytic film was defined with a Kapton tape as shown in Fig. S1. The specimen was connected to a metal wire using silver paste. During the electrochemical measurements, the defined area of the working electrode was immersed into the electrolyte solution.



**Figure S1.** Picture of MoS<sub>2</sub>/Au/Ti/Si working electrode of which the geometric area was defined to 1 cm<sup>2</sup> by a Kapton tape. The specimen was connected to a metal wire using silver paste.

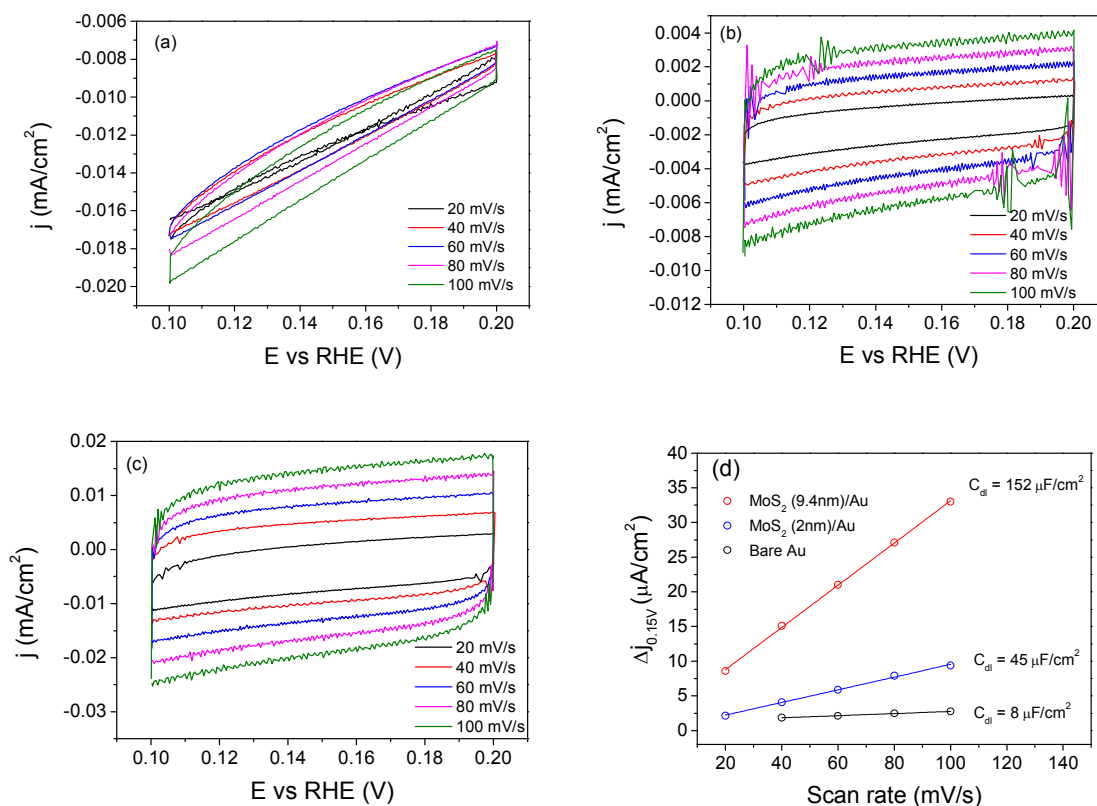


**Ohmic potential drop (iR) correction:** The ohmic drop correction was performed with a series resistance ( $R_s$ ) determined by electrochemical impedance measurement, according to the method given in Ref. S1. In our electrochemical setup, the series resistance may contain four components arising from the resistance in the wiring ( $R_{\text{wiring}}$ , e.g., electrode cables, alligator clips, Ag paste), the resistance in the Au substrate ( $R_{\text{gold}}$ ), the solution resistance ( $R_{\text{sol}}$ ) and the resistance due to the  $\text{MoS}_2$  film itself ( $R_{\text{film}}$ ). The electrochemical impedance measurements were performed at open circuit potential from 200 kHz to 50 mHz, using an AC amplitude of 25 mV. For all specimens, the series resistance was determined to be  $\sim 2.5 \Omega$  by the real component of the impedance at high frequencies where the imaginary component is negligible, as shown in the Nyquist plot of Fig. S2. This reveals that the contribution of  $R_{\text{film}}$  to the series resistance is negligible. Therefore the iR correction using the measured  $R_s$  does not overestimate the HER activity. The experimental overpotential ( $\eta_{\text{exp}}$ ) was corrected by subtracting the ohmic drop ( $iR_s$ ) as the equation of  $\eta_{\text{corr}} = \eta_{\text{exp}} - iR$ .



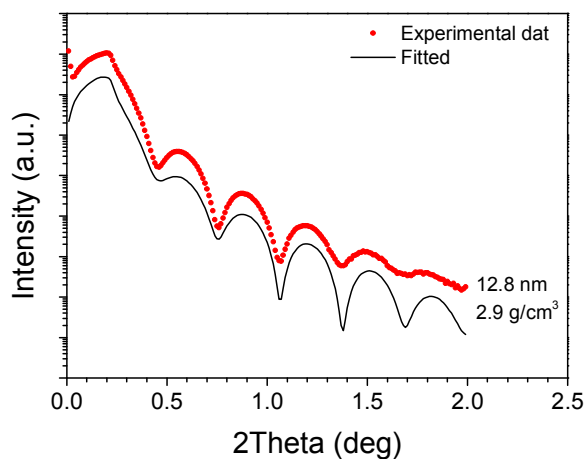
**Figure S2.** Nyquist plots of  $\text{MoS}_2$  thin films and bare gold specimens performed at open circuit potential from 200 kHz to 50 mHz, using an AC amplitude of 25 mV. The series resistance was measured to be  $\sim 2.5 \Omega$  for all specimens.

**Capacitance measurements:** Since the effective surface area of the catalyst film is linearly proportional to the double layer capacitance ( $C_{dl}$ ), we performed cyclic voltammetry (CV) to obtain the values of  $C_{dl}$  for the MoS<sub>2</sub> films and the bare Au specimen in a potential range of 0.1 ~ 0.2 V with various scan rates (20, 40, 60, 80, 100 mV/s), according to the method in the Ref. S2. The cathodic ( $J_c$ ) and anodic ( $J_a$ ) current densities of the cyclic voltammograms in Figs. S3 (a-c) should be mainly originated from the charging of the electric double layer, because there is no faradaic process in the voltage range. In Fig. S3d, the current density difference ( $\Delta j$ ) of  $J_c$  and  $J_a$  at 0.15 V vs RHE was plotted against the scan rate and fitted to a linear line. The slope represents a doubling of the double layer capacitance. The double layer capacitance of the bare Au, MoS<sub>2</sub> (2 nm)/Au, and MoS<sub>2</sub> (9.4 nm)/Au specimens are 8, 45, and 152  $\mu\text{F}/\text{cm}^2$ , respectively. Comparing the double layer capacitances of the two MoS<sub>2</sub> specimens, the thinner film has a  $C_{dl}$  value 3.4 times smaller than the thicker film. This reveals that MoS<sub>2</sub> did not completely cover Au in the MoS<sub>2</sub> (2 nm)/Au specimen due to the ultrathin thickness.



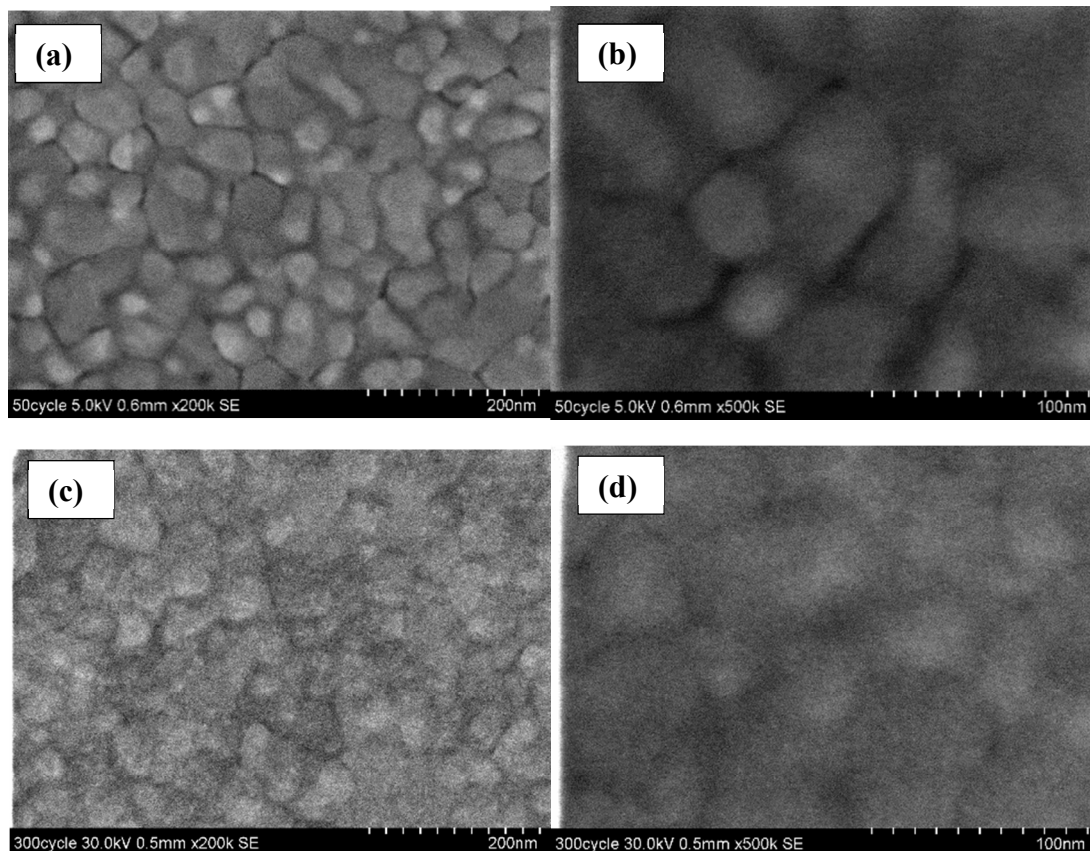
**Figure S3.** (a-c) Cyclic voltammograms in the range of 0.1 ~ 0.2 V vs RHE for the bare Au (a), MoS<sub>2</sub> (2 nm)/Au (b) and MoS<sub>2</sub> (9.4 nm)/Au (c) specimens. (d) The differences in current density ( $\Delta j = j_a - j_c$ ) at 0.15 V vs RHE plotted against scan rate. The each plot was fitted to a linear line to determine the value of  $C_{dl}$ .

**Grazing incidence X-ray reflectivity (XRR):** For the MoS<sub>2</sub> film grown on a bare Si wafer, we performed low angle XRR measurement in the  $2\theta$  range of  $0 \sim 2^\circ$  in order to obtain the film density. The experimental data was fitted for the film to be 12.8 nm with a density of 2.9 g/cm<sup>3</sup> as shown in Fig. S4. The thickness determined by XRR roughly agrees with the thickness (11.5 nm) determined by spectroscopic ellipsometer with a Tauc-Lorentz dispersion function.<sup>S3</sup> In addition, the density of the film reveals that the film is less dense in comparison to the crystalline MoS<sub>2</sub>, due to the amorphous nature of the film grown at 100 °C.



**Figure S4.** Low angle XRR data and its fitted curve for MoS<sub>2</sub>/Si specimen.

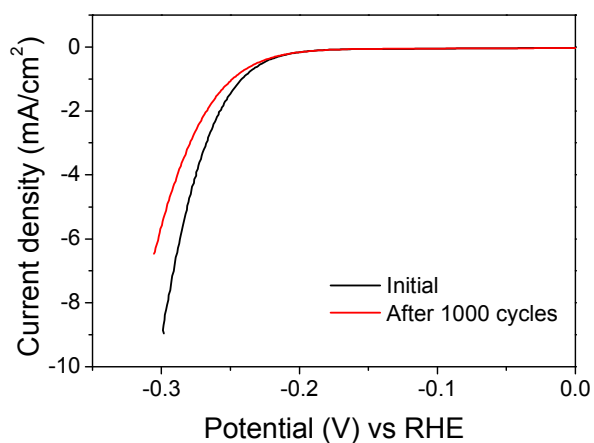
**Scanning electron microscopy (SEM) images:** The high resolution SEM images were taken on the MoS<sub>2</sub> film grown on Au. For these images, any metal, which is generally coated on an insulating specimen to avoid the charging effect by electron beam, was not coated on the specimen, because the MoS<sub>2</sub> film is considerably conducting (Fig. 5). For the MoS<sub>2</sub> (2 nm)/Au, the grains of Au are clearly visible due to the ultrathin thickness. However the MoS<sub>2</sub> (9.4 nm)/Au specimen shows that the grains and their boundaries are covered by the film, even though the surface is still rough.



**Figure S5.** SEM images of MoS<sub>2</sub> (2 nm)/Au (a - b) and MoS<sub>2</sub> (9.4 nm)/Au (c - d).



**Stability test of ALD-MoS<sub>2</sub> catalyst:** For the stability test of the ALD-MoS<sub>2</sub>/Au catalyst, the cyclic voltammetry (CV) was repeated for 1000 cycles between 0.205 ~ -0.195 V vs. RHE in 0.5 M H<sub>2</sub>SO<sub>4</sub>. There is a significant loss of activity after 1000 CV cycling.



**Figure S6.** Stability of ALD-MoS<sub>2</sub>/Au catalyst before and after 1000 CV cycling.

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